

Li Wang

List of Publications by Year in descending order

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Version: 2024-02-01

30
papers

722
citations

567144

15
h-index

526166

27
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31
all docs

31
docs citations

31
times ranked

485
citing authors

#	ARTICLE	IF	CITATIONS
1	Effect of SiC/Si template residual stress on GaN residual stress and crystal quality. <i>Physica Status Solidi (B): Basic Research</i> , 2016, 253, 824-828.	0.7	1
2	Silicon etching using only Oxygen at high temperature: An alternative approach to Si micro-machining on 150µm Si wafers. <i>Scientific Reports</i> , 2016, 5, 17811.	1.6	6
3	Growth mechanism for alternating supply epitaxy: the unique pathway to achieve uniform silicon carbide films on multiple large-diameter silicon substrates. <i>RSC Advances</i> , 2016, 6, 16662-16667.	1.7	10
4	Piezo-Hall effect in single crystal p-type 3C-SiC(100) thin film grown by low pressure chemical vapor deposition. <i>RSC Advances</i> , 2016, 6, 31191-31195.	1.7	9
5	Kinetic surface roughening and wafer bow control in heteroepitaxial growth of 3C-SiC on Si(111) substrates. <i>Scientific Reports</i> , 2015, 5, 15423.	1.6	13
6	Vertically Conductive Single-Crystal SiC-Based Bragg Reflector Grown on Si Wafer. <i>Scientific Reports</i> , 2015, 5, 17026.	1.6	13
7	Orientation dependence of the pseudo-Hall effect in p-type 3C-SiC four-terminal devices under mechanical stress. <i>RSC Advances</i> , 2015, 5, 56377-56381.	1.7	25
8	The effect of strain on the electrical conductance of p-type nanocrystalline silicon carbide thin films. <i>Journal of Materials Chemistry C</i> , 2015, 3, 1172-1176.	2.7	29
9	Charge transport and activation energy of amorphous silicon carbide thin film on quartz at elevated temperature. <i>Applied Physics Express</i> , 2015, 8, 061303.	1.1	41
10	The effect of device geometry and crystal orientation on the stress-dependent offset voltage of 3C-SiC(100) four terminal devices. <i>Journal of Materials Chemistry C</i> , 2015, 3, 8804-8809.	2.7	25
11	Si Surface Preparation for Heteroepitaxial Growth of SiC Using <i>In Situ</i> Oxidation. <i>Materials Science Forum</i> , 2015, 821-823, 205-208.	0.3	1
12	The Dependence of Offset Voltage in p-Type 3C-SiC van der Pauw Device on Applied Strain. <i>IEEE Electron Device Letters</i> , 2015, 36, 708-710.	2.2	25
13	Pseudo-Hall effect in single crystal 3C-SiC(111) four-terminal devices. <i>Journal of Materials Chemistry C</i> , 2015, 3, 12394-12398.	2.7	17
14	Fundamental piezoresistive coefficients of p-type single crystalline 3C-SiC. <i>Applied Physics Letters</i> , 2014, 104, .	1.5	70
15	Piezoresistive Effect of p-Type Single Crystalline 3C-SiC Thin Film. <i>IEEE Electron Device Letters</i> , 2014, 35, 399-401.	2.2	51
16	Thickness dependence of the piezoresistive effect in p-type single crystalline 3C-SiC nanothin films. <i>Journal of Materials Chemistry C</i> , 2014, 2, 7176-7179.	2.7	58
17	Misorientation dependent epilayer tilting and stress distribution in heteroepitaxially grown silicon carbide on silicon (111) substrate. <i>Thin Solid Films</i> , 2014, 564, 39-44.	0.8	19
18	Novel Electrical Characterization of Thin 3C-SiC Films on Si Substrates. <i>Science of Advanced Materials</i> , 2014, 6, 1542-1547.	0.1	12

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19	Orientation-dependent stress relaxation in hetero-epitaxial 3C-SiC films. Applied Physics Letters, 2013, 102, .	1.5	59
20	Dependence of chemical composition and bonding of amorphous SiC on deposition temperature and the choice of substrate. Journal of Non-Crystalline Solids, 2011, 357, 1063-1069.	1.5	11
21	Demonstration of p-type 3C-SiC grown on 150mm Si(100) substrates by atomic-layer epitaxy at 1000°C. Journal of Crystal Growth, 2011, 329, 67-70.	0.7	63
22	Growth of 3C-SiC on 150-mm Si(100) substrates by alternating supply epitaxy at 1000 °C. Thin Solid Films, 2011, 519, 6443-6446.	0.8	94
23	InGaN/GaN Multiple Quantum Well Blue LEDs on 3C-SiC/Si Substrate. Materials Science Forum, 2011, 679-680, 801-803.	0.3	0
24	Transition between amorphous and crystalline phases of SiC deposited on Si substrate using H ₃ SiCH ₃ . Journal of Crystal Growth, 2009, 311, 4442-4446.	0.7	22
25	Aluminum induced <i>in situ</i> crystallization of amorphous SiC. Applied Physics Letters, 2009, 94, .	1.5	13
26	Deep void formation mechanism in Si(100) during its carbonization reaction with C ₂ H ₂ . Thin Solid Films, 2007, 515, 6824-6826.	0.8	3
27	Polytype Control in 6H-SiC Grown via Sublimation Method. Materials Science Forum, 2006, 527-529, 95-98.	0.3	6
28	Stacking faults in SiC crystal grown by spontaneous nucleation sublimation method. Journal of Crystal Growth, 2006, 292, 192-196.	0.7	16
29	Identification of Polytypes in Sublimation Grown 4H-SiC Crystals by High Resolution X-Ray Diffractometry. Materials Science Forum, 2006, 527-529, 451-454.	0.3	2
30	Color Chart for Thin SiC Films Grown on Si Substrates. Materials Science Forum, 0, 740-742, 279-282.	0.3	7